

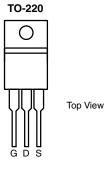
IRFB4110PBF-VB Datasheet N-Channel 100 V (D-S) MOSFET

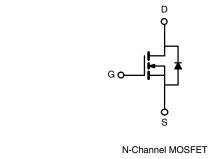
PRODUCT SUMMARY				
V _{DS} (V)	100			
$R_{DS(on)} (\Omega)$ at $V_{GS} = 10 V$	0.0030			
I _D (A) ^a	180			
Configuration	Single			

FEATURES

- Trench Power MOSFET
- Package with Low Thermal Resistance
- AEC-Q101 Qualified^d
- + 100 % $\rm R_g$ and UIS Tested







ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)					
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	100	V	
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current	T _C = 25 °C ^a		180		
Continuous Drain Current	T _C = 125 °C	I _D	140		
Continuous Source Current (Diode Conduction) ^a		I _S	180	А	
Pulsed Drain Current ^b		I _{DM}	480		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	73		
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	266	mJ	
Maximum Power Dissipation ^b	T _C = 25 °C	PD	250	W	
Maximum Power Dissipation ²	T _C = 125 °C		83	٧V	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C	

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	40	°C/W
Junction-to-Case (Drain)		R _{thJC}	0.6	0/10

Notes

a. Base on Tc = 25°C.

b. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

c. When mounted on 1" square PCB (FR-4 material).

d. Parametric verification ongoing.

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static					<u> </u>			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0, I_D = 250 \ \mu A$		100	-	-	v	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$		3.0	3.5	v	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$		-	-	± 100	nA	
		$V_{GS} = 0 V$	V _{DS} = 100 V	-	-	1		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V _{DS} = 100 V, T _J = 125 °C	-	-	50	μA	
		$V_{GS} = 0 V$	V _{DS} = 100 V, T _J = 175 °C	-	-	500	-	
On-State Drain Current ^a	I _{D(on)}	V _{GS} = 10 V	$V_{DS} \ge 5 V$	120	-	-	Α	
		V _{GS} = 10 V	I _D = 20 A	-	0.0030	-	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A, T _J = 125 °C	-	0.0064	-		
		V _{GS} = 10 V	I _D = 20 A, T _J = 175 °C	-	0.0080	-		
Forward Transconductanceb	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		-	82	-	S	
Dynamic ^b							<u> </u>	
Input Capacitance	C _{iss}			-	5780	7230		
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	V _{GS} = 0 V V _{DS} = 25 V, f = 1 MHz		3070	3840	pF	
Reverse Transfer Capacitance	C _{rss}			-	305	385	1	
Total Gate Charge ^c	Qg			-	125	190		
Gate-Source Charge ^c	Q _{gs}	V _{GS} = 10 V	$V_{DS} = 50 \text{ V}, \text{ I}_{D} = 70 \text{ A}$	-	28	-	nC	
Gate-Drain Charge ^c	Q _{gd}			-	46	-		
Gate Resistance	R _g	f = 1 MHz		1.6	3.3	5	Ω	
Turn-On Delay Time ^c	t _{d(on)}	$\begin{array}{l} V_{\text{DD}} = 50 \; V, \; R_{\text{L}} = 0.7 \; \Omega \\ I_{\text{D}} \cong 70 \; A, \; V_{\text{GEN}} = 10 \; V, \; R_{\text{g}} = 1 \; \Omega \end{array}$		-	16	25		
Rise Time ^c	t _r			-	110	165	ns	
Turn-Off Delay Time ^c	t _{d(off)}			-	40	60		
Fall Time ^c	t _f			-	12	20		
Source-Drain Diode Ratings and Char	acteristics ^b							
Pulsed Current ^a	I _{SM}			-	-	480	Α	
Forward Voltage	V _{SD}	$I_{\rm F} = 100 \rm A, V_{\rm GS} = 0$		-	0.9	1.5	V	

Notes

a. Pulse test; pulse width $\leq 300~\mu\text{s},$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

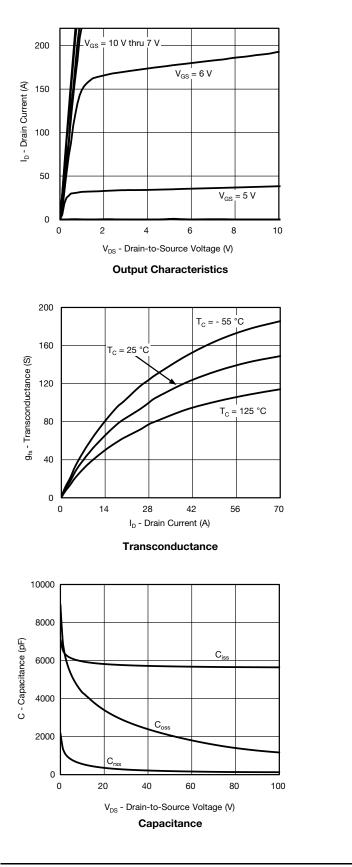
c. Independent of operating temperature.

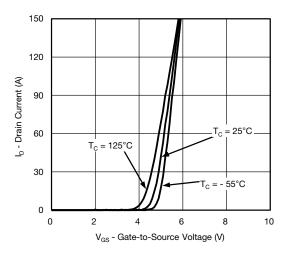
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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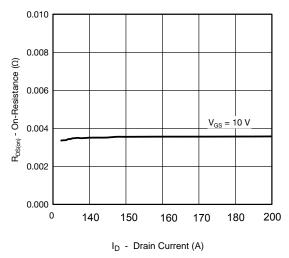


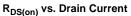
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)

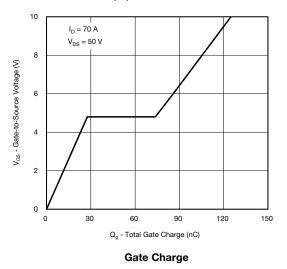




Transfer Characteristics

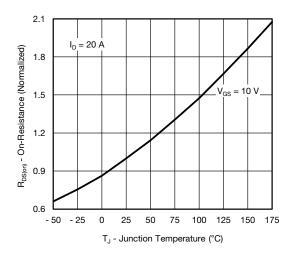




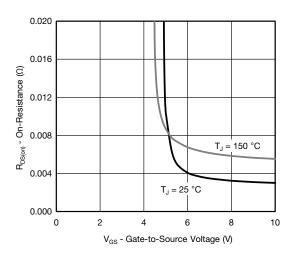




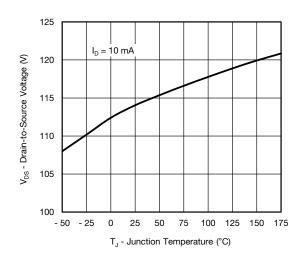
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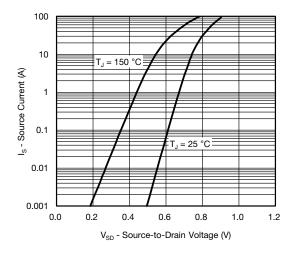
On-Resistance vs. Junction Temperature



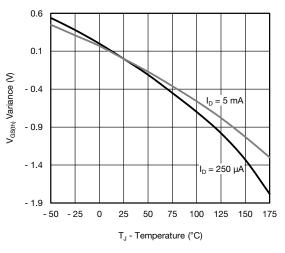
On-Resistance vs. Gate-to-Source Voltage



Drain Source Breakdown vs. Junction Temperature



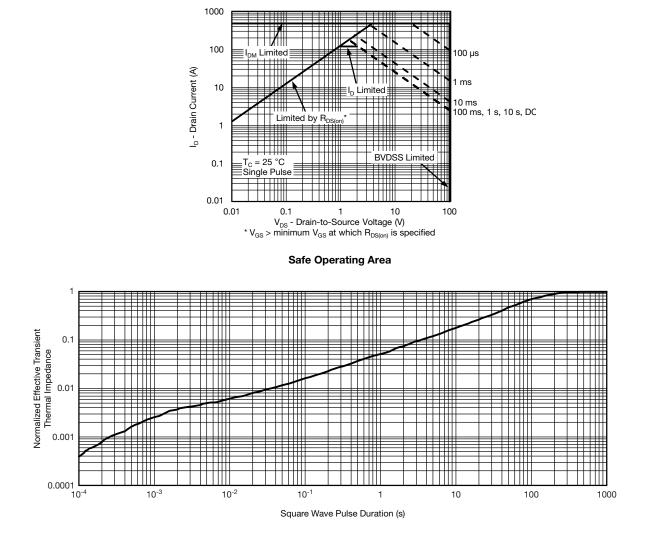
Source Drain Diode Forward Voltage



Threshold Voltage



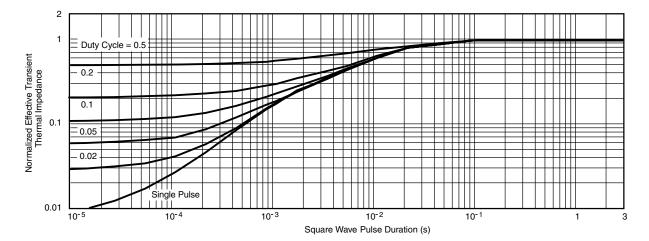
THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

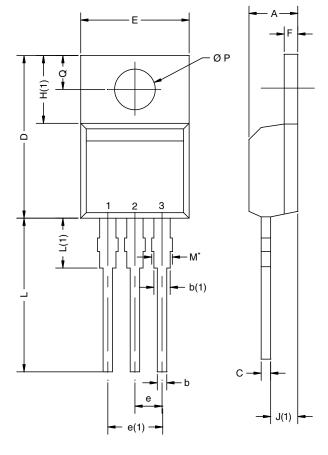
Note

- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction to Ambient (25 °C)
 - Normalized Transient Thermal Impedance Junction to Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



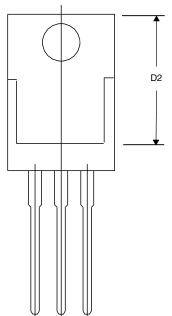
TO-220AB



	MILLIN	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
А	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
D2	12.19	12.70	0.480	0.500		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØР	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
	ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471					

Note

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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